# UNİSYS

DATE:

May 15, 1997

TO:

J.Lohr/311

FROM:

K. Sahu/300.1 ドラー

SUBJECT:

Radiation Report on: LM137 (7703403XA)

Project:

MAP SUBSYSTEMS

Job#:

M78117

Project part #:

LM137 (7703403XA)

cc: T. Miccolis/311 A. Sharma/311 OFA Library/300,1

PPM-97-020

A radiation evaluation was performed on I.M137 (770340XA) to determine the total dose tolerance of these parts. A brief summary of the test results is provided below. For detailed information, refer to Tables I through IV and Figure 1.

The total dose testing was performed using a Co<sup>60</sup> gamma ray source. During the radiation testing, eight parts were irradiated under bias (see Figure 1 for bias configuration) and two parts were used as control samples. The total dose radiation levels were 2.5, 5.0, 7.5, 10.0, 15.0, 20.0, 30.0, and 50.0 kRads. The dose rate was between 0.06 and 0.50 kRads/hour (see Table II for radiation schedule). After the 50.0 kRad exposure, the parts were annealed for 120 hours at 25°C. After each radiation exposure and annealing treatment, parts were electrically tested according to the test conditions and the specification limits\*\* listed in Table III.

Initial electrical measurements were made on 10 samples. Eight samples (SN's 13, 14, 15, 16, 17, 18, 19, and 20) were used as radiation samples while SN's 11 and 12 were used as control samples. All parts passed all tests during initial electrical measurements.

All parts passed all tests upon irradiation to 7.5 kRads. No significant degradation was noted in any of the parts.

After the 10.0 kRad irradiation, only SN 16 met the specification limit for the Delta IADJ\_I test. Readings for the parts were within the range of -4.1 to -10.6 $\mu$ A against the specification limit of  $\pm 5\mu$ A. All parts continued to pass all other tests.

After the 15.0 kRad irradiation, all parts exceeded the specification limits for the IADJ\_41.25V and Delta\_IADJ\_1 tests. Readings were within the range of -66 to -160  $\mu$ A against specification limits of 25  $\mu$ A (min) and 100  $\mu$ A (max) for IADJ\_41.25V and 144 to 272  $\mu$ A for Delta\_IADJ\_1. Four parts (SN's 14, 15, 18, and 19) failed IADJ\_425V with all readings within the range of 89 to 111  $\mu$ A against specification limits of 25  $\mu$ A (min) and 100  $\mu$ A (max). All parts continued to pass all other tests.

After the 20.0 kRad irradiation, all parts continued to degrade in both IADJ -41.25V and Delta\_IADJ\_1. Only SN 20 passed IADJ\_-41.25V with readings within the range of 88 to 219  $\mu$ A. Readings for Delta\_IADJ\_1 were within the range of -22 to -122  $\mu$ A. All parts continued to pass all other tests.

After the 30.0 kRad irradiation, the parts continued to degrade with all parts failing IADJ\_-4.25V, IADJ\_-41.25V and Delta\_IADJ\_1. Readings were within the range of 380 to 621  $\mu$ A, 697 to 1276  $\mu$ A, and -339 to -654  $\mu$ A, respectively. All parts continued to pass all other tests.

The term Rads, as used in this document, means Rads(silicon). All radiation levels cited are cumulative.

<sup>&</sup>quot;These are manufacturer's pre-irradiation data specification limits. The manufacturer provided no post-irradiation limits at the time these tests were performed.

After annealing the parts for 120 hours at 25°C, the parts did not show any significant recovery in IADJ\_4.25V, IADJ\_41.25V and Delta\_IADJ\_1. Readings were in the range of 181 to 360  $\mu$ A, 474 to 762  $\mu$ A, and -281 to -529  $\mu$ A, respectively. All parts continued to pass all other tests.

Table IV provides a summary of the test results with the mean and standard deviation values for each parameter after each irradiation exposure and annealing step.

Any further details about this evaluation can be obtained upon request. If you have any questions, please call me at (301) 731-8954.

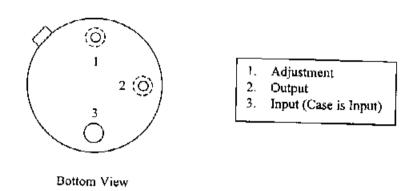
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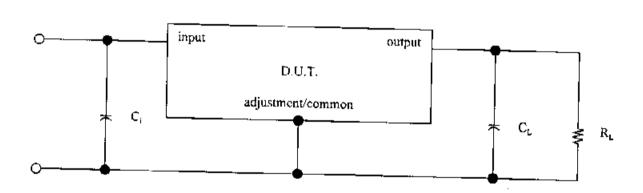
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Figure 1. Radiation Bias Circuit for LM137

### TO-39 Metal Can Package





Note: Resistor is  $250\Omega \pm 5\%$  ¼W. Capacitors are 1µf, 50V; however, capacitors may not be required if the parts do not oscillate (are stable).

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### TABLE I. Part Information

Generic Part Number:

LM137

MAP-POWER Part Number

7703403XA

Charge Number;

EE78117

Manufacturer:

Linear Technology Corp.

Lot Date Code (LDC):

9638

Quantity Tested:

10

Serial Number of Control Samples:

11, 12

Serial Numbers of Radiation Samples:

13, 14, 15, 16, 17, 18, 19, 20

Part Function:

Adjustable Negative Voltage Regulator

Part Technology:

Bipolar

Package Style:

TO-39

Test Equipment:

A540

Test Engineer:

A. Naji

No radiation tolerance/hardness was guaranteed by the manufacturer for this part.

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## TABLE II. Radiation Schedule for LM137 EVENT.......DATE I) INITIAL ELECTRICAL MEASUREMENTS ...... 04/07/97 POST-15.0 KRAD FLECTRICAL MEASUREMENT 04/30/97 9) 120 HOUR ANNEALING @25°C ..... Effective Dose Rate = 30,000 RADS/22 DAYS = 56.8 RADS/HOUR=0.016 RADS/SEC

PARTS WERE IRRADIATED AND ANNEALED UNDER BIAS, SEE FIGURE 1.

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Table III. Electrical Characteristics of LM137 /1/2

Test	<b>.</b>			Spec. Lim,			
#	Parameters /1	Units	Test Conditions	min	max		
1	IQ4.25V	mA	$V_{IN} = -4.25$	0.2	3.0		
2	IQ14.25V	mΛ	$V_{IN} = -14.25$	0.2	3.0		
3	IQ41.25V	mA	$V_{py} = -41.25$	1.0	5.0		
4	IADJ -4.25V	μA	$V_{IN} = -4.25$ , $I_L = 5 \text{mA}$	25	100		
5	IADJ41.25V	μΑ	$V_{IN} = -41.25$ , $I_{L} = 5mA$	25	100		
6	Delta_IADJ_!	μΑ	$-41.25 \le V_{1K} \le -4.25$ , $I_L = 5 \text{mA}$	-5,0	5.0		
7	V_Out_1	V	$V_{IN} = -4.25 \text{ V}, l_1 = 5 \text{ mA}$	-1.275	-1.225		
8	V Out 2	V	$V_{1N} = -41.25V$ , $I_1 = 5mA$	-1.275	-1.225		
9	V_Out_3		$V_{IN} = -6.25V, I_L = 5mA$	-1,275	-1.225		
_10	V_Line1	mV	-41.25 < V <sub>IN</sub> < -4.25	-9.0	9.0		
11	V_Load1	mV	$V_{IN} = -6.25V$ , 5mA $< I_L < 200$ mA	-6.0	6.0		
12	V_Load2	mV	$V_{IN} = -4.25V$ , 5mA $< I_1 < 400$ mA	-12.0	12.0		
13	V_Out 4	V	$V_{IN} = -41.25V$ , $5mA \le I_L \le 50mA$	-1.275	-1.225		
14	V_Out 5	V	$V_{IN} = -4.25V$ , $5mA \le I_L \le 50mA$	-1.275	-1.225		

### Notes:

<sup>1/</sup> These are the manufacturer's non-irradiated data sheet specification limits. No post-irradiation limits were provided by the manufacturer at the time the tests were performed

<sup>2/</sup> Refer to MIL-M-38510/11803, Table I, for details of test parameters and conditions.

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Table III. Electrical Characteristics of LM137 /1/2

Test				Spec.	Lim.	
#	Parameters /1	Units	Test Conditions	min	max	
1	1Q4.25V	mA	$V_{1N} = -4.25$	0.2	3.0	
2	IQ14.25V	m A	$V_{IN} = -4.25$	0.2	3.0	
3	IQ -41.25V	mA	V <sub>IN</sub> 4.25	1.0	5.0	
4	1ADJ4.25V	μA	$V_{18} = -4.25, I_L = 5mA$	25	100	
5	IADJ41.25V	μA	$V_{DI} = -4.25, I_{L} = 5 \text{mA}$	25	100	
6	Delta IADJ_1	μA	$-41.25 \le V_{IN} \le -4.25$ , $I_L = 5 \text{mA}$	-5.0	5.0	
7	V_Out_1	V		-1.275	-1.225	
8	V_Out_2	V	$V_{IN} = -41.25V, I_L = 5mA$	-1.275	-1,225	
9	V_Out_3	v	$V_{tN} = -6.25 V, I_L - 5 mA$	-1.275	-1.225	
10	V Line1	mV	$-41.25 \le V_{IN} \le -4.25$	-9.0	9.0	
11	V_Load!	шV	$V_{IN} = -6.25V, 5mA \le I_1 \le 200mA$	-6.0	6.0	
12	V_Load2	mV	$V_{lN} = -4.25V, 5mA \le l_L \le 400mA$	-12.0	12.0	
13	V_Our 4	٧	$V_{IN} = -41.25 \text{ V}, 5 \text{ mA} \le I_{L} \le 50 \text{ mA}$	-1.275	-1.225	
14	V_Out_5	v		-1.275	-1.225	

#### Notes:

- 1/ These are the manufacturer's non-irradiated data sheet specification limits. No post-irradiation limits were provided by the manufacturer at the time the tests were performed
- 2/ Refer to MIL-M-38510/11803, Table I, for details of test parameters and conditions.

TABLE IV: Summary of Electrical Measurements after Total Dose Exposures and Annealing for LM137 /1

							Total Dose Exposure (kRads)											Anneali	ing			
					Ini	tial	2.5	5.0 7.5 10.0 15.0				15.0		20.0		30.0		168 hours				
Test		Spec. Lim. /2		1																@25°C		
#	Parameters	Units	min	m2x	mean	sd	mean	sd	mean	sď	mean	sd	mean	sd	mean	sd	mean	sd	mean	sd	mean	sd
L	IQ4.25V	mA	0.2	3.0	1.3	0.04	1.3	0.04	1.3	0.04	1.3	0.04	1.3	0.04	1.3	0.05	1.3	0.04	1.3	0.04	1.3	0.04
2	IQ14.25V	mA	0.2	3.0	1.3	0.04	1.3	0.04	1.3	0.04	1.3	0.04	1.3	0.04	1.3	0.85	1.3	0.04	1.3	0.04	1.4	0.02
3	1Q41.25V	mA	1.0	5.0	2,1	0.06	2.1	0.06	2.1	0.05	2.1	0.06	2.1	0.06	2.1	0.06	2.1	0.05	2.1	<b>0.</b> 06	<b>2.</b> I	0.06
4	IADJ4.25V	uA	25	100	71	1.6	69	1.8	69	1.9	68	1.5	69	2.1	99	12.9	83	10.5	485	103	256	54
5	IADJ41.25V	вA	25	100	74	1.8	72	1.7	72	1.7	71	1.8	76	3.1	228	48	172	48	978	223	188	133
6	Delta_IADJ_I	uA	-5.0	5.0	-2.0	0.05	-3.1	0.05	-3.0	0.1	-3.0	0	-7.9	2.1	-130	35	-89	38	-493	120	-125	83
7	V_Out_1	v	-1.275	-1.225	-1.256	0.001	-1.254	0.002	-1.253	0.002	-1.251	0.002	-1.250	0.002	-1.247	0.003	-1.243	0.003	-1.239	<b>0</b> .003	-1.240	0.003
8	V_Out_2	V	-1.275	-1.225	-1.256	0.001	-1.254	<b>0</b> .002	-1.253	0.002	-1.251	0.002	-1.250	0.002	-1.247	0.003	-1.243	0.003	-1.239	0.003	-1.240	0.003
9	V_Out_3	V	-1.275	-1.225	-1.258	0.001	-1,246	0.002	-1.255	0.002	-1.252	0.002	-1.251	0.002	-1.248	0.003	-1.244	0.003	-1.240	0.003	-1.241	0.003
10	V_Line1	mV	-9.0	9.0	-0.6	0.1	-0.5	0.1	-0.5	0.1	-0.6	0.1	-0.6	0.1	-0.6	0.1	-0.7	0.1	-0.5	0.2	-0.6	0.2
11	V_Lond1	mV	-6.0	6.0	3.3	0.9	3.3	0.9	3.0	0.6	3.0	0.6	3.3	1.7	2.7	0.5	2.6	0.5	2.5	0.3	2.47	0.7
12	V_Load2	mV	-12.0	12.0	6.1	2.0	6.0	1.7	5.2	1.0	5.3	1.4	6.1	3.5	4.6	1.0	4.5	1.2	4.4	0.7	4.3	0.9
13	V_Quc_4	V	-1.275	-1.225	-1.249	0.002	-1.248	0.002	-1.248	<b>0</b> .002	-1.246	0.003	-1.244	0.005	-1.242	0.003	-1.239	0.003	-1.235	0.003	-1.236	0.003
14	V_Out_5	V	-1.275	-1.225	-1.252	0.001	-1.251	0.002	-1.250	0.002	-1.249	0.003	-1.247	0.003	-1.245	0. <b>00</b> 3	-1.241	0.003	-1.237	0.003	-1.238	0.003

#### Notes:

- 1/ The mean and standard deviation values were calculated over the eight parts irradiated in this testing. The control samples remained constant throughout the testing and are not included in this table.
- 2/ These are manufacturer's pre-irradiation data sheet specification limits. No post-irradiation limits were provided by the manufacturer at the time the tests were performed.

Radiation sensitive parameters: IADJ\_4.25V, IADJ\_41.25V, and Delta\_IADJ\_1.

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